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ABSTRACT:

PURPOSE: To shorten the testing time by providing a memory selector which simultaneously accesses plural bank memories, automatically selecting the output of the memory, and comparing it with test data.

CONSTITUTION: In a memory test mode, a memory selector 7 outputs chip selecting signals to bank memories 2 to 5, simultaneously reads the data, and a selector control 12 applies a memory output selective signal to a data selector 13. Next, the selector 13 applies the selected memory output data to a data comparator 15, and the comparator 15 compares the data with the test data set in a data register 14 beforehand. Thus a testing operation can be completed in the ready cycle of the memory 2 by a processor 16.